

<b>Notice of References Cited</b>	Application/Control No. 10/533,564		Applicant(s)/Patent Under Reexamination IWASAKI	
	Examiner Michael P. Mooney		Art Unit 2883	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,573,984	06-2003	Jung et al.	356/73
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Hideo Itoh, et al., "Multidimensional Optical Interconnections Using Beam-Scanning Laser Diodes", Electronics and Communications in Japan, Part 11: Electronics, Scripta Technica, New York, U.S., Vol 75, No. 11, (11/01/1992), pp. 32-41, XP000381545, ISSN: 8756-663X.
	V	
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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